

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10629020	EZELL, R. WILLIAM
	<b>Examiner</b>	<b>Art Unit</b>
	Lee, Siu M	2611

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
375	316	12/15/2006	Siu M. Lee
327	553	12/15/2006	Siu M. Lee
330	303	12/15/2006	Siu M. Lee

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
US-PGPUB	12/15/2006	Siu M. Lee
USPAT	12/15/2006	Siu M. Lee
USOCR	12/15/2006	Siu M. Lee
EPO	12/15/2006	Siu M. Lee
JPO	12/15/2006	Siu M. Lee
DERWENT	12/15/2006	Siu M. Lee
IBM_TDB	12/15/2006	Siu M. Lee
Discussed the application with Chieh Fan	12/15/2006	Siu M. Lee
EAST	4/19/2007	Siu M. Lee
Discuss the application with Chieh Fan	4/19/2007	Siu M. Lee

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>